

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(324/609.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:18
L2	1	(324/602,600.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:18
L3	22	(324/111,522,713.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L4	7	(327/9,55,56,337.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L5	12	(327/50-54.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L6	3	(327/91-96.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L7	7	(341/122-125.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19

L8	8	(341/172.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L9	4	(363/76,78,89.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L10	29	(323/282,353.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L11	30	(455/127.1.cccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L12	8	((((check\$\$3 detect\$\$3 sens\$\$3 measur\$\$5 comput\$\$3 calculat\$\$3 \$2valuat\$\$3 \$2valuat\$\$3 examin\$\$5 test\$\$3 determin\$\$3 recogniz\$\$3 inspect\$\$3 anal\$\$5 monitor\$\$3 diagnos\$\$3 identif\$\$7) near\$\$3 current) and (resist\$\$5 FET transistor) and samp\$\$3 and switch\$\$5 and \$4charg\$\$5 and (Convey\$\$4 feed\$\$4 advanc\$\$4 transfer\$\$4 deliver\$\$4 rotat\$\$4 roll\$\$4) and voltage and (state mode condition status stage) and ground and first and second and third and fourth),clm.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 12:55
L13	1	("20050151543").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/08/31 13:19
L14	446	(check\$\$3 detect\$\$3 sens\$\$3 measur\$\$5 comput\$\$3 calculat\$\$3 \$2valuat\$\$3 \$2valuat\$\$3 examin\$\$5 test\$\$3 determin\$\$3 recogniz\$\$3 inspect\$\$3 anal\$\$5 monitor\$\$3 diagnos\$\$3 identif\$\$7) near\$\$3 ((bit\$\$1direction\$\$3 two\$\$1way two\$\$1direction both\$\$1direction ((two both) adj (way direction))) near\$\$3 current) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:44

L16	102	114 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:49
L17	7	114 and (capacitor sampling) same (samp\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:46
L18	21	114 and (samp\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 16:01